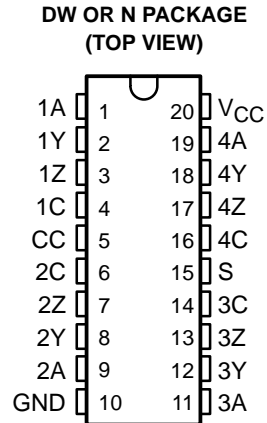


SN75151 QUADRUPLE DIFFERENTIAL LINE DRIVER

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- Meets or Exceeds the Requirement of ANSI EIA/TIA-422-B
- High-Impedance Output State for Party-Line Operation
- High Output Impedance in Power-Off Condition
- Low Input Current to Minimize Loading
- Single 5-V Supply
- 40-mA Sink- and Source-Current Capability
- High-Speed Schottky Circuitry
- Low Power Requirements



description

This line driver is designed to provide differential signals with high current capability on balanced lines. This circuit provides strobe and enable inputs to control all four drivers and provides an additional enable input for each driver. The output circuits have active pullup and pulldown resistors and are capable of sinking or sourcing 40 mA.

The SN75151 meets all requirements of ANSI EIA/TIA-422-B and Federal Standard 1020. The SN75151 is characterized for operation from 0°C to 70°C.

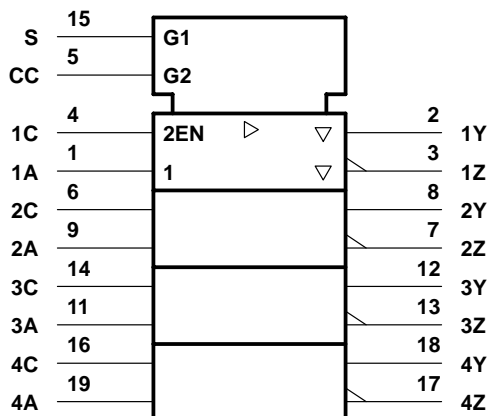
FUNCTION TABLE

INPUTS				OUTPUTS	
ENABLE CC	ENABLE C	STROBE S	DATA A	Y	Z
L	X	X	X	Z	Z
X	L	X	X	Z	Z
H	H	L	X	L	H
H	H	X	L	L	H
H	H	H	H	H	L

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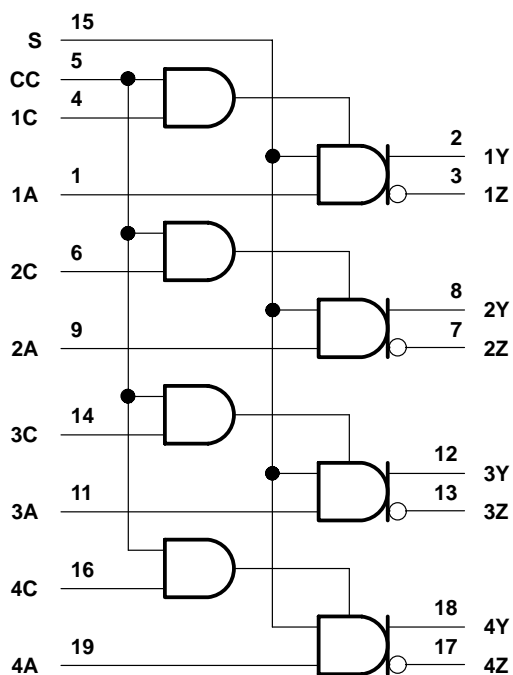
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logic symbol†

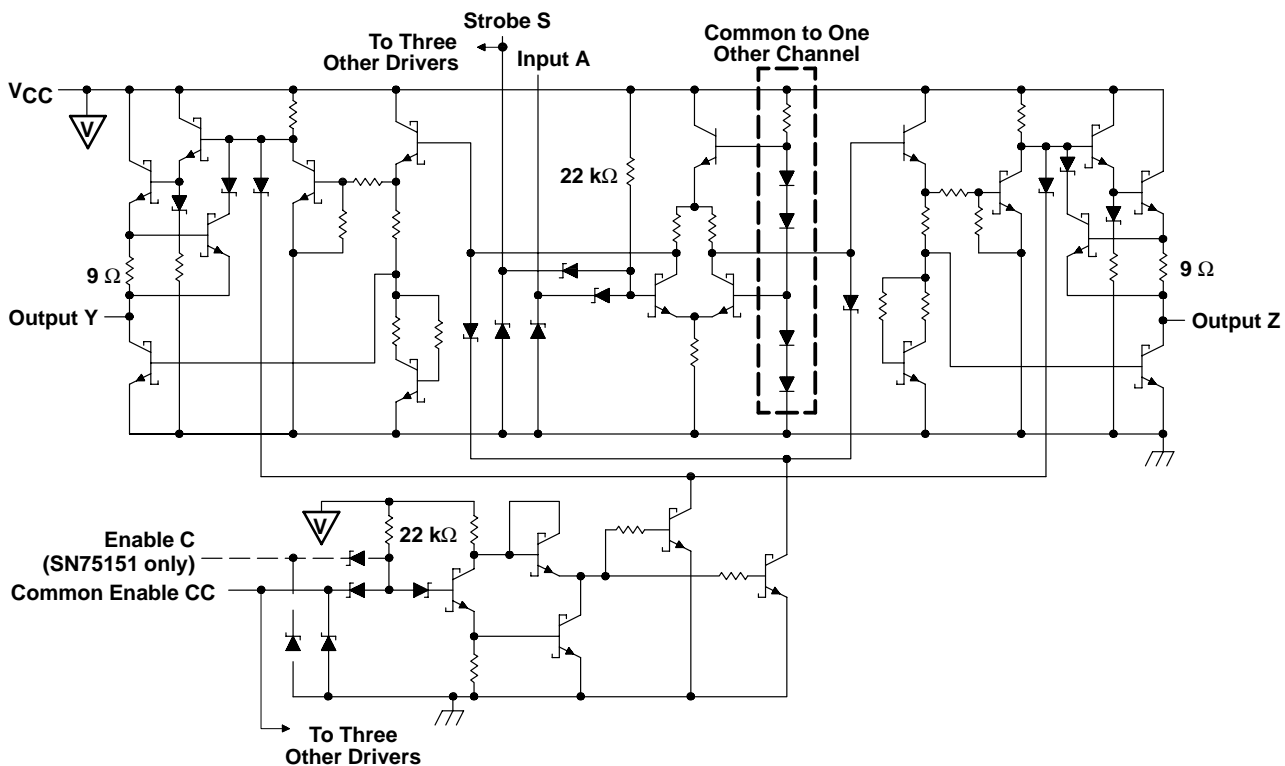


† This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)



schematic



Resistor values shown are nominal.

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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage, V_{CC} (see Note 1)	7 V
Input voltage, V_I	5.5 V
Continuous total dissipation	See Dissipation Rating Table
Operating free-air temperature range, T_A	0°C to 70°C
Storage temperature range, T_{stg}	–65°C to 150°C
Lead temperature 1,6 mm (1/16 inch) from case for 10 seconds	260°C

† Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTE 1: All voltage values, except differential output voltage V_{OD} , are with respect to network ground terminal.

DISSIPATION RATING TABLE

PACKAGE	$T_A \leq 25^\circ\text{C}$ POWER RATING	OPERATING FACTOR ABOVE $T_A = 25^\circ\text{C}$	$T_A = 70^\circ\text{C}$ POWER RATING
DW	1125 mW	9.0 mW/°C	720 mW
N	1150 mW	9.2 mW/°C	736 mW

recommended operating conditions

	MIN	NOM	MAX	UNIT
Supply voltage, V_{CC}	4.75	5	5.25	V
High-level input voltage, V_{IH}	2			V
Low-level input voltage, V_{IL}			0.8	V
Common-mode output voltage, V_{OC}	–0.25		6	V
High-level output current, I_{OH}			–40	mA
Low-level output current, I_{OL}			40	mA
Operating free-air temperature, T_A	0		70	°C



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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS†		MIN	TYP‡	MAX	UNIT	
V _{IK}	Input clamp voltage	V _{CC} = MIN, I _I = -12 mA	CC, S			-2	V	
			All others		-0.9	-1.5		
V _{OH}	High-level output voltage	V _{CC} = MIN, V _{IH} = 2 V, V _{IL} = MAX,	I _{OH} = -20 mA	2.5			V	
			I _{OH} = -40 mA	2.4				
V _{OL}	Low-level output voltage	V _{CC} = MIN, V _{IL} = MAX, V _{IH} = 2 V, I _{OL} = 40 mA				0.5	V	
V _{OD1}	Differential output voltage	V _{CC} = MAX, I _O = 0		3.4	2V _{OD2}		V	
V _{OD2}	Differential output voltage	V _{CC} = MIN		2	2.8		V	
Δ V _{OD}	Change in magnitude of differential output voltage§	V _{CC} = MIN		±0.01		±0.4	V	
V _{OC}	Common-mode output voltage¶	V _{CC} = MAX	R _L = 100 Ω, See Figure 1	1.8		3	V	
		V _{CC} = MIN		1.6		3		
Δ V _{OC}	Change in magnitude of common-mode output voltage§	V _{CC} = MIN or MAX			±0.02		±0.4	V
I _{OZ}	Off-state (high-impedance-state) output current	V _{CC} = MAX, Enable at 0.8 V	V _O = 0.5 V			-20	μA	
			V _O = 2.5 V			20		
			V _O = V _{CC}			20		
I _O	Output current with power off	V _{CC} = 0	V _O = 6 V		0.1	100	μA	
			V _O = -0.25 V		-0.1	-100		
			V _O = -0.25 V to 6 V			±100		
I _I	Input current at maximum input voltage	V _{CC} = MAX, V _I = 5.5 V				0.1	mA	
I _{IH}	High-level input current	V _{CC} = MAX, V _I = 2.4 V	C(SN75151), A			20	μA	
			CC, S			80		
I _{IL}	Low-level input current	V _{CC} = MAX, V _I = 0.4 V	C(SN75151), A			-0.36	mA	
			CC, S			-1.6		
I _{OS}	Short-circuit output current#	V _{CC} = MAX		-50	-90	-150	mA	
I _{CC}	Supply current (both drivers)	V _{CC} = MAX, No load	Outputs disabled		30	60	mA	
			Outputs enabled		60	80		

† For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

‡ All typical values are at T_A = 25°C and V_{CC} = 5 V except for V_{OC}, for which V_{CC} is as stated under test conditions.

§ Δ|V_{OD}| and Δ|V_{OC}| are the changes in magnitudes of V_{OD} and V_{OC}, respectively, that occur when the input is changed from a high level to a low level.

¶ In ANSI Standard EIA/TIA-422-B, V_{OC}, which is the average of the two output voltages with respect to ground, is called output offset voltage, V_{OS}.

Only one output should be shorted at a time, and duration of the short-circuit should not exceed one second.

switching characteristics over recommended operating free-air temperature range, $V_{CC} = 5\text{ V}$ (unless otherwise noted)

PARAMETER		TEST CONDITIONS		MIN	TYP†	MAX	UNIT
t _{PLH}	Propagation delay time, low- to high-level output	C _L = 30 pF, Termination A,	R _L = 100 Ω, See Figure 2		15	30	ns
t _{PHL}	Propagation delay time, high- to low-level output				15	30	ns
t _{PLH}	Propagation delay time, low- to high-level output	C _L = 30 pF, See Figure 2	Termination B,		13	25	ns
t _{PHL}	Propagation delay time, high- to low-level output				13	25	ns
t _{TLH}	Transition time, low- to high-level output	C _L = 30 pF, Termination A,	R _L = 100 Ω, See Figure 2		12	20	ns
t _{THL}	Transition time, high- to low-level output				12	20	ns
t _{PZH}	Output enable time to high level	C _L = 30 pF, See Figure 3	R _L = 60 Ω,		18	35	ns
t _{PZL}	Output enable time to low level	C _L = 30 pF, See Figure 4	R _L = 111 Ω,		20	35	ns
t _{PHZ}	Output disable time from high level	C _L = 30 pF, See Figure 3	R _L = 60 Ω,		19	30	ns
t _{PLZ}	Output disable time from low level	C _L = 30 pF, See Figure 4	R _L = 111 Ω,		13	30	ns
Overshoot factor		R _L = 100 Ω, See Figure 2	Termination C,			10	%

† All typical values are at T_A = 25°C.

PARAMETER MEASUREMENT INFORMATION

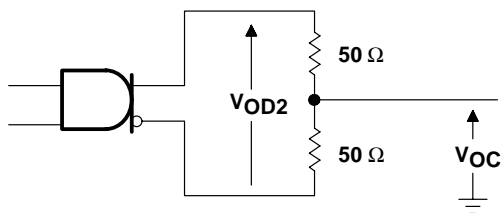
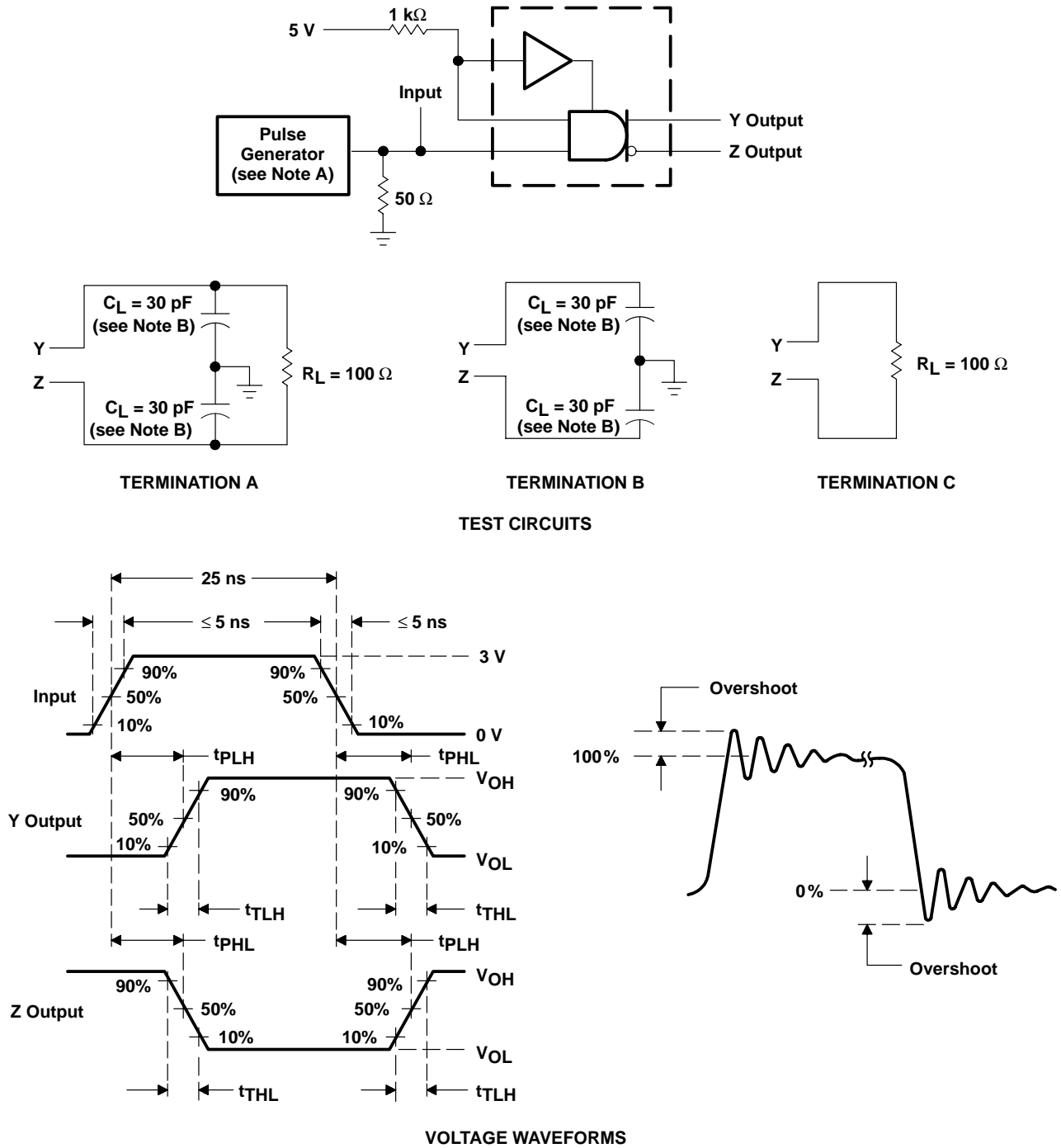


Figure 1. Differential and Common-Mode Output Voltages

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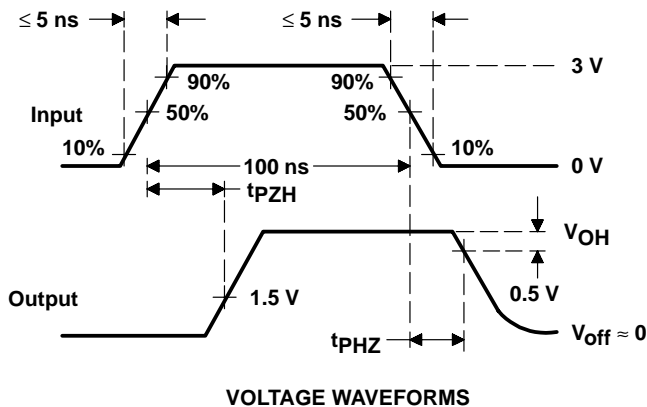
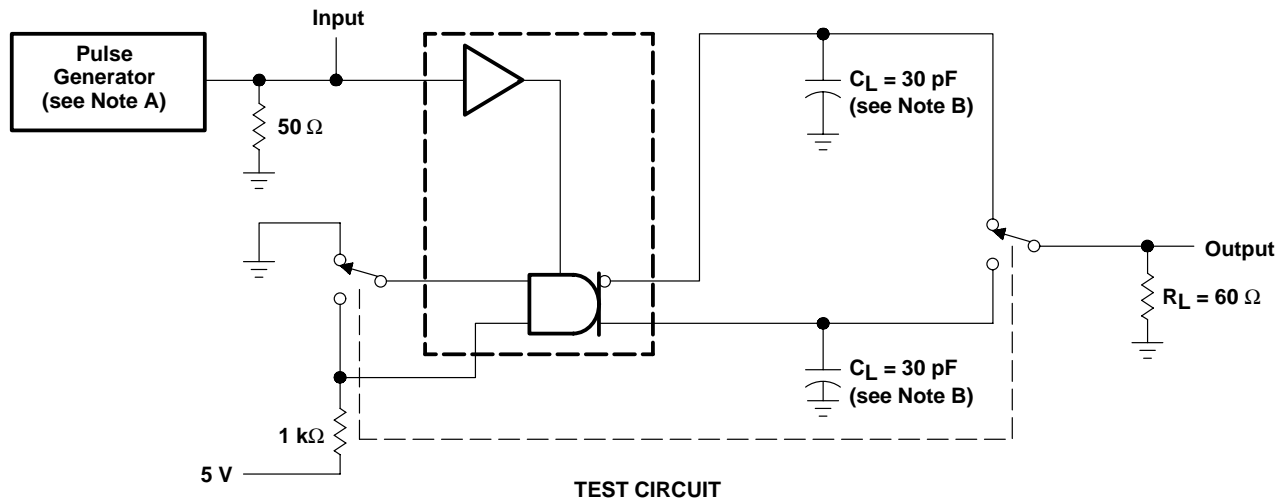
PARAMETER MEASUREMENT INFORMATION



NOTES: A. The pulse generator has the following characteristics: Z_O = 50 Ω, PRR ≤ 10 MHz.
B. C_L includes probe and jig capacitance.

Figure 2. Test Circuits, Voltage Waveforms, and Overshoot Factor

PARAMETER MEASUREMENT INFORMATION



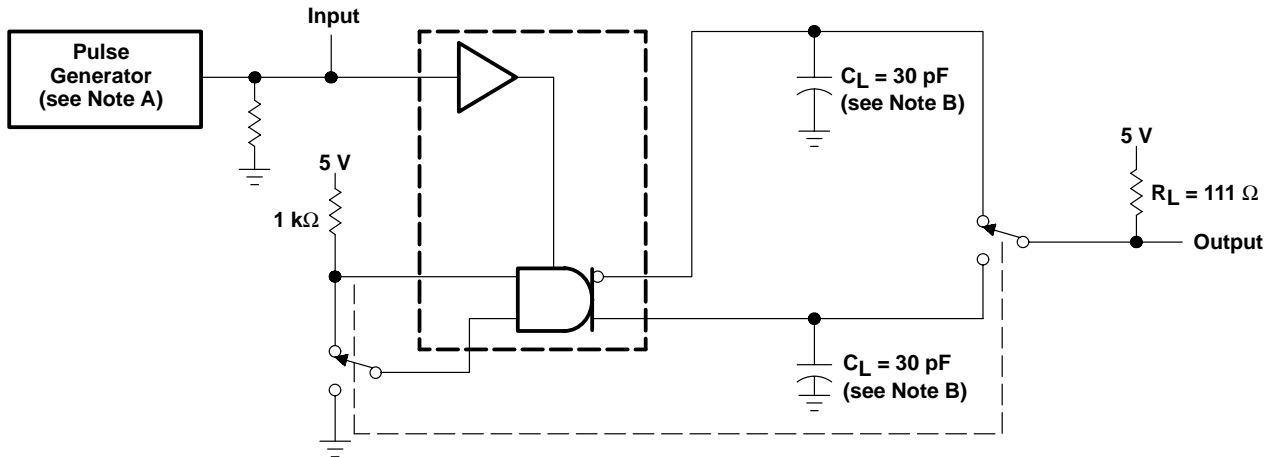
- NOTES: A. The pulse generator has the following characteristics: $Z_O = 50\ \Omega$, $\text{PRR} \leq 500\ \text{kHz}$.
 B. C_L includes probe and jig capacitance.

Figure 3. Test Circuit and Voltage Waveforms

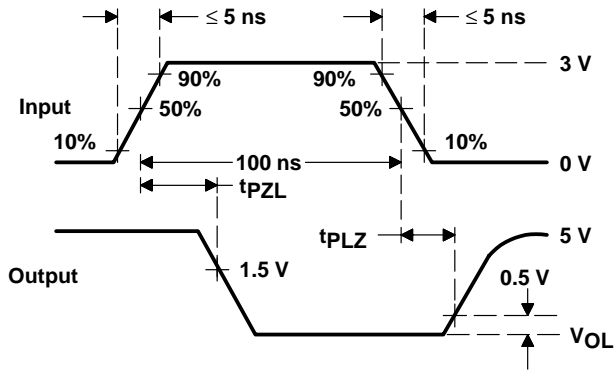
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PARAMETER MEASUREMENT INFORMATION



TEST CIRCUIT

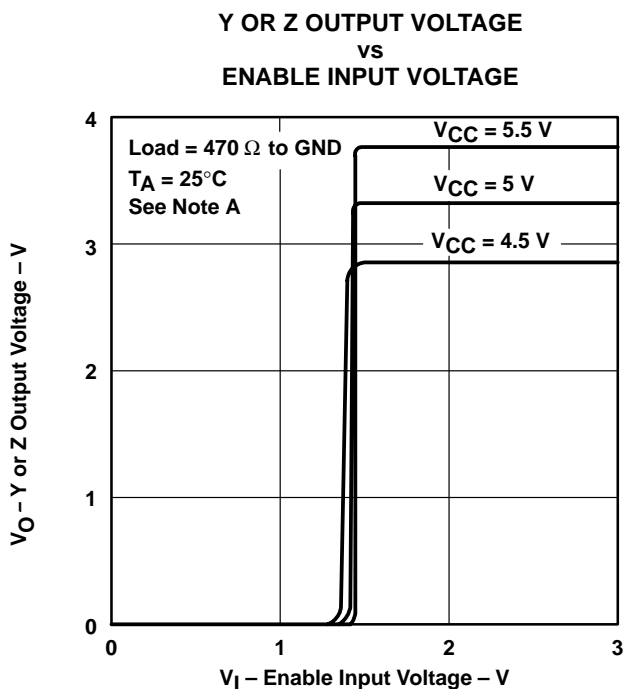
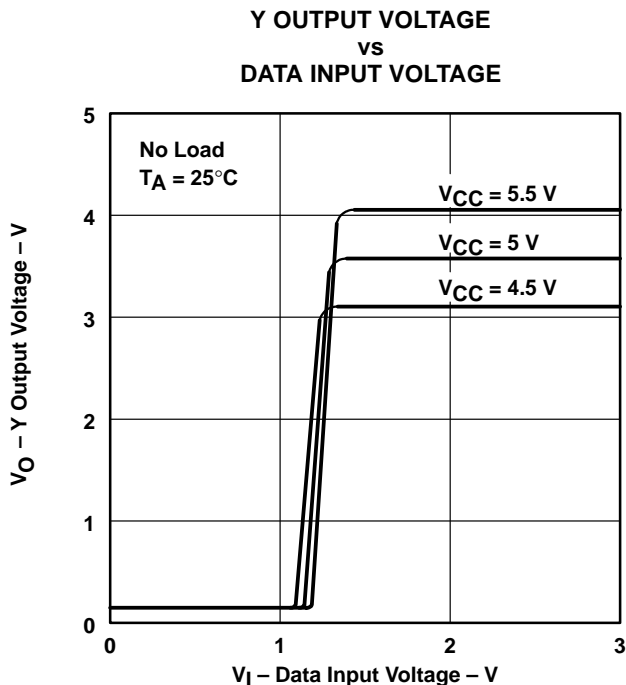


VOLTAGE WAVEFORMS

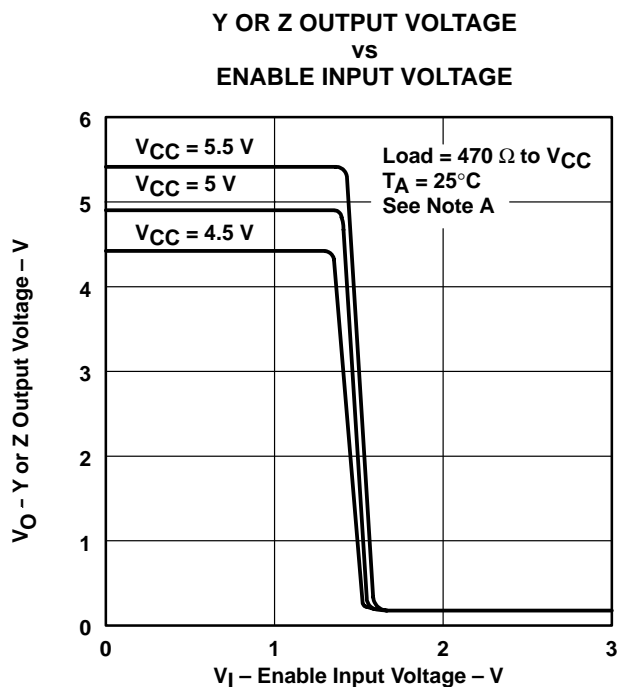
- NOTES: A. The pulse generators have the following characteristics: $Z_O = 50 \Omega$, $PRR \leq 500 \text{ kHz}$.
 B. C_L includes probe and jig capacitance.

Figure 4. Test Circuit and Voltage Waveforms

TYPICAL CHARACTERISTICS



NOTE A: The A input is connected to V_{CC} during the testing of the Y outputs and to ground during testing of the Z outputs.



NOTE A: The A input is connected to GND during the testing of the Y outputs and to V_{CC} during the testing of the Z outputs.

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TYPICAL CHARACTERISTICS

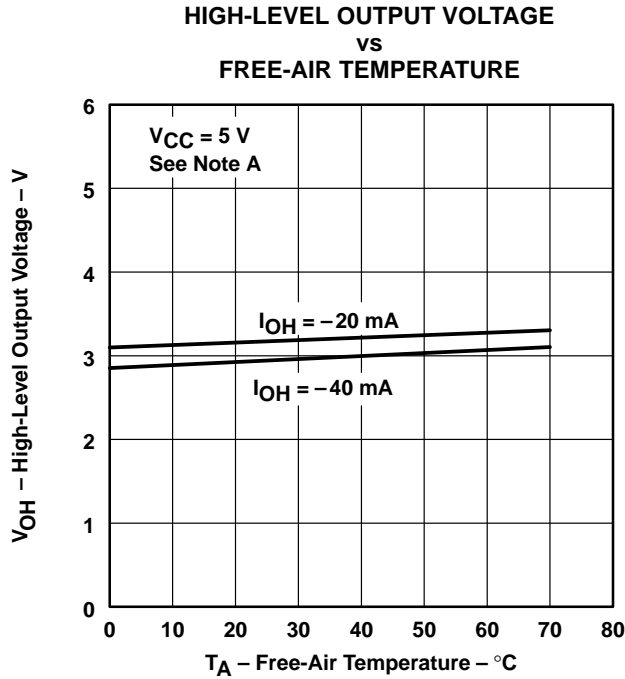


Figure 8

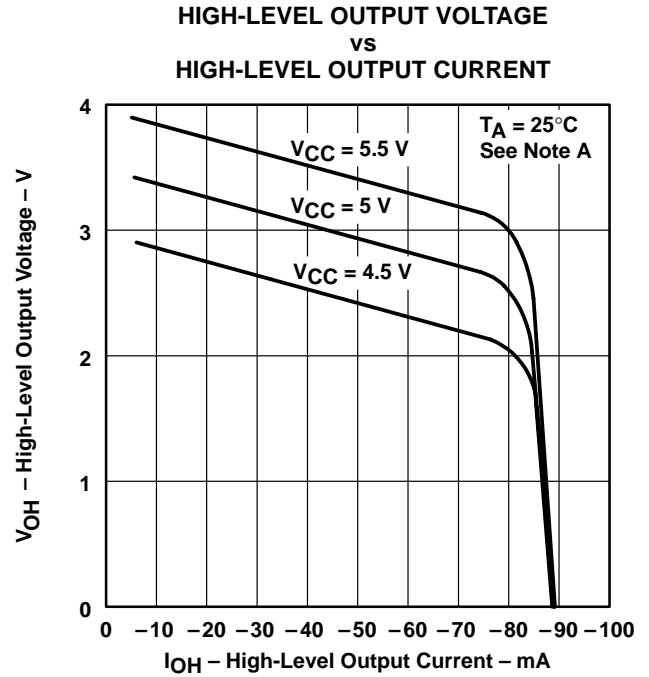


Figure 9

NOTE A: The A input is connected to V_{CC} during the testing of the Y outputs and to ground during testing of the Z outputs.

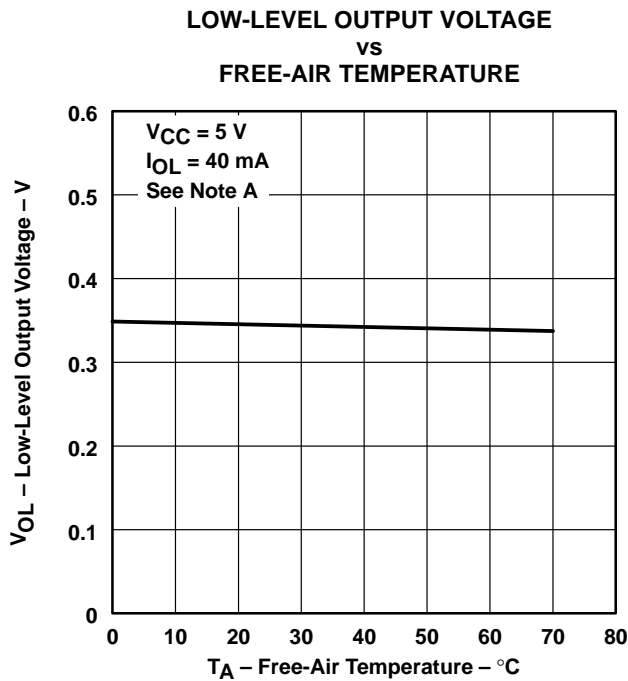


Figure 10

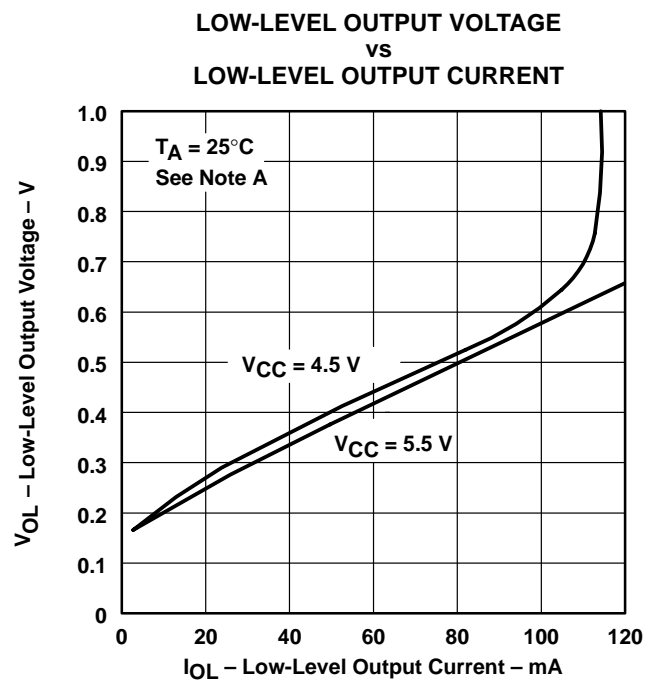


Figure 11

NOTE A: The A input is connected to GND during the testing of the Y outputs and to V_{CC} during the testing of the Z outputs.

TYPICAL CHARACTERISTICS

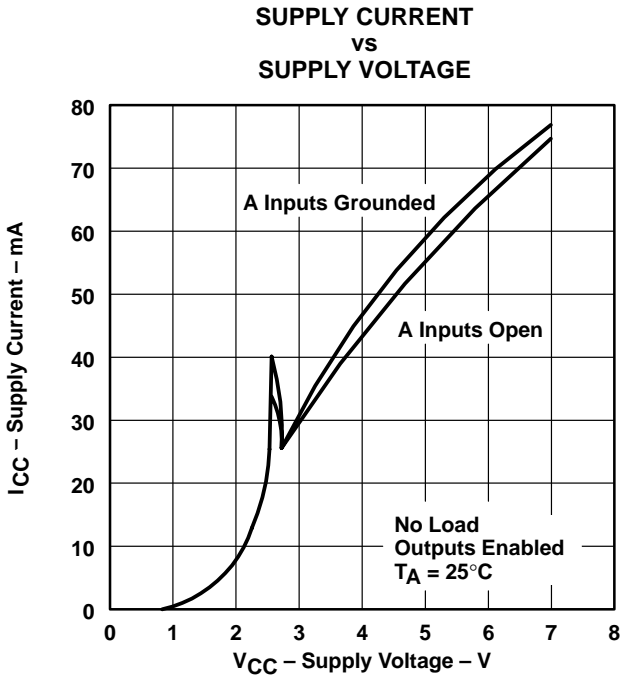


Figure 12

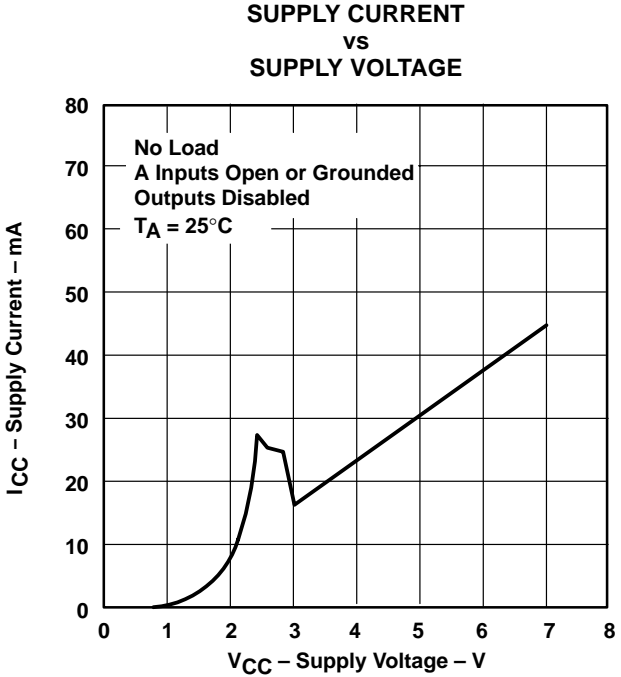


Figure 13

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